INTEGRATED CIRCUITS, SILICON MONOLITHIC,

ADVANCED CMOS OCTAL BUS BUFFERS

WITH INVERTED 3-STATE OUTPUTS,

BASED ON TYPE 54AC240

ESCC Detail Specification No. 9401/042

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Pages 1 to 43

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SCC

space components
coordination group

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		SCCG Chairman	ESA Director General or his Deputy
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DOCUMENTATION CHANGE NOTICE

Rev. Letter	Rev. Date	Reference	CHANGE Item	Approved DCR No.

TABLE OF CONTENTS

1.   **GENERAL**

1.1   **SCOPE**

This specification details the ratings, physical and electrical characteristics, test and inspection data for a silicon, monolithic, advanced CMOS Octal Bus Buffer, with inverted 3-State Outputs, based on Type 54AC240. It shall be read in conjunction with ESA/SCC Generic Specification No. 9000, the requirements of which are supplemented herein.

1.2   **COMPONENT TYPE VARIANTS**

Variants of the basic type integrated circuits specified herein, which are also covered by this specification, are given in Table 1(a).

1.3   **MAXIMUM RATINGS**

The maximum ratings, which shall not be exceeded at any time during use or storage, applicable to the integrated circuits specified herein, are as scheduled in Table 1(b).

1.4   **PARAMETER DERATING INFORMATION (FIGURE 1)**

Not applicable.

1.5   **PHYSICAL DIMENSIONS**

As per Figure 2.

1.6   **PIN ASSIGNMENT**

As per Figure 3(a).

1.7   **TRUTH TABLE**

As per Figure 3(b).

1.8   **CIRCUIT SCHEMATIC**

As per Figure 3(c).

1.9   **FUNCTIONAL DIAGRAM**

As per Figure 3(d).

1.10   **HANDLING PRECAUTIONS**

These devices are susceptible to damage by electrostatic discharge. Therefore, suitable precautions shall be employed for protection during all phases of manufacture, testing, packaging, shipment and any handling.

These components are categorised as Class 2 with a Minimum Critical Path Failure Voltage of 4000 Volts.

1.11   **INPUT AND OUTPUT PROTECTION NETWORKS**

Protection networks shall be incorporated into each input and output as shown in Figure 3(e).

TABLE 1(a) - TYPE VARIANTS

VARIANT	CASE	FIGURE	LEAD MATERIAL AND/OR FINISH
01	D.I.L.	2(a)	G4
02	FLAT	2(b)	G4
03	CHIP CARRIER	2(c)	2
04	CHIP CARRIER	2(c)	4

TABLE 1(b) - MAXIMUM RATINGS

No.	CHARACTERISTICS	SYMBOL	MAXIMUM RATINGS	UNITS	REMARKS
1	Supply Voltage	V_{DD}	-0.5 to $+6.0$	V	Note 1
2	Input Voltage	V_{IN}	-0.5 to $V_{DD} + 0.5$	V	Notes 1, 2
3	Output Voltage	V_{OUT}	-0.5 to $V_{DD} + 0.5$	V	Notes 1, 3
4	Device Dissipation (Continuous)	P_D	1056	mW	Note 4
5	Supply Current	I_{DDop}	192	mA	
6	Operating Temperature Range	T_{op}	-55 to $+125$	°C	T_{amb}
7	Storage Temperature Range	T_{stg}	-65 to $+150$	°C	
8	Soldering Temperature For FP and DIP For CCP	T_{sol}	$+265$ $+245$	°C °C	Note 5 Note 6

NOTES

1. Device is functional for $3.0V \le V_{DD} \le 5.5V$.

2. Input current limited to $I_{IC} = \pm 20mA$.

3. Output current limited to $I_{OUT} = \pm 50mA$.

4. The maximum device dissipation is determined by I_{DDop} max. (mA) × 5.5V.

5. Duration 10 seconds maximum at a distance of not less than 1.5mm from the device body and the same lead shall not be resoldered until 3 minutes have elapsed.

6. Duration 5 seconds maximum and the same terminal shall not be resoldered until 3 minutes have elapsed.

FIGURE 1 - PARAMETER DERATING INFORMATION

Not applicable.

FIGURE 2 - PHYSICAL DIMENSIONS

FIGURE 2(a) - DUAL-IN-LINE PACKAGE, 20-PIN
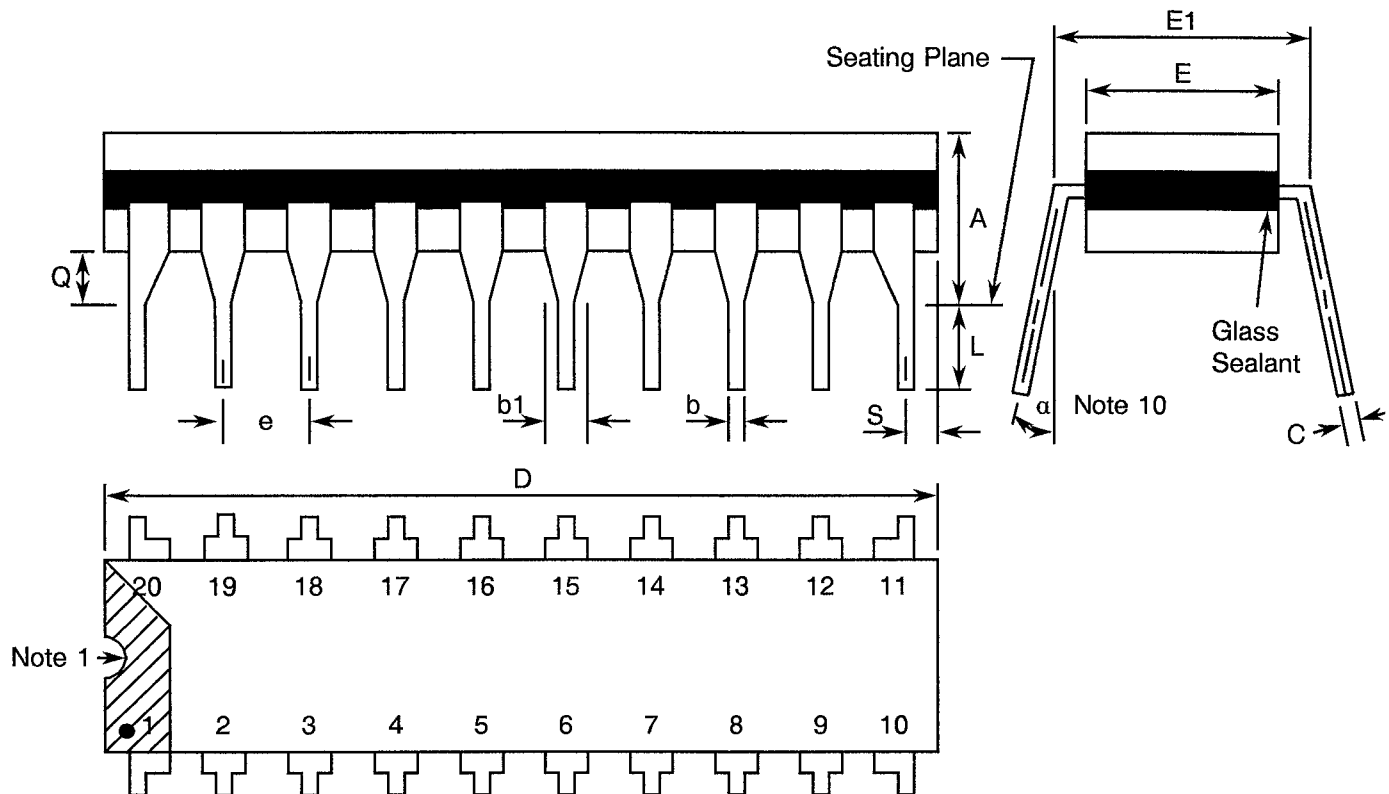
SYMBOL	MILLIMETRES		NOTES
	MIN	MAX	
A	-	5.08	
b	0.35	0.56	8
b1	1.40	1.77	8
C	0.20	0.38	8
D	23.88	25.15	4
E	6.10	7.49	4
E1	7.62 TYPICAL		
e	2.54 TYPICAL		6, 9
L	3.10	4.31	8
Q	0.25	1.02	3
S	0.51	1.27	7
α	0°	15°	10

NOTES: See Page 10.

FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)

FIGURE 2(b) - FLAT PACKAGE, 20-PIN
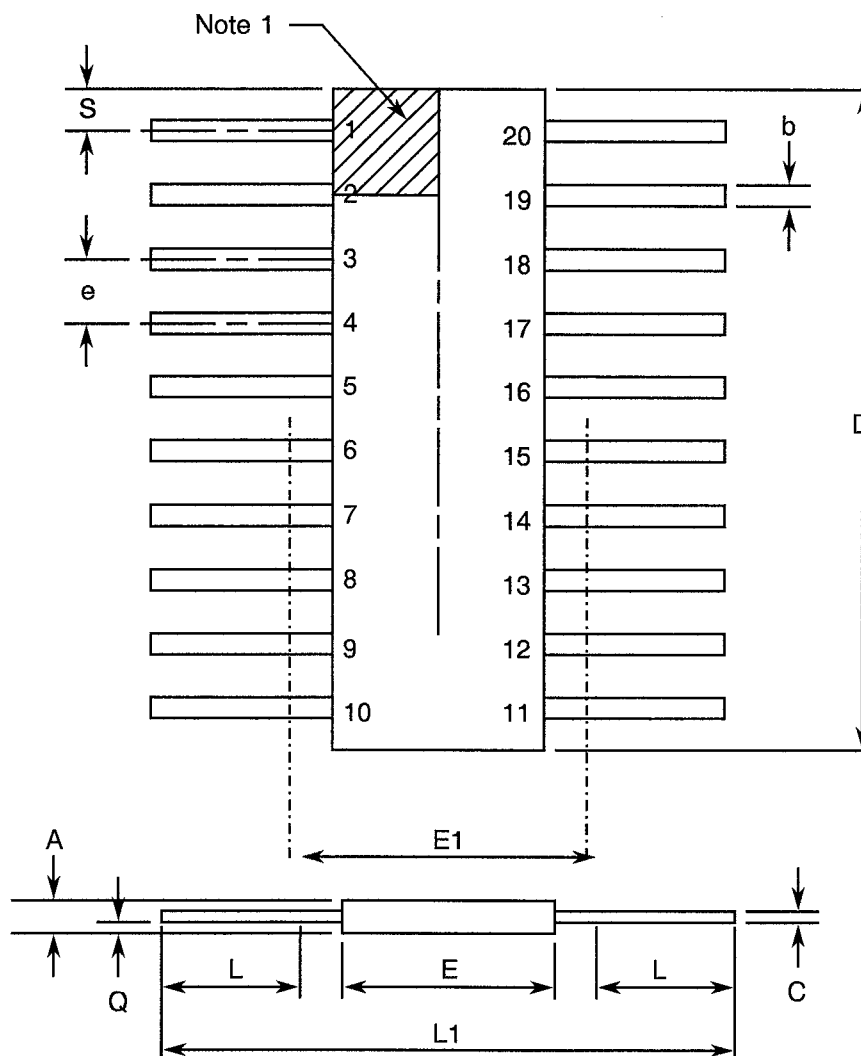
SYMBOL	MILLIMETRES		NOTES
	MIN	MAX	
A	1.52	2.16	
b	0.36	0.56	8
C	0.08	0.17	8
D	-	13.08	4
E	5.84	7.24	
E1	7.61 TYPICAL		4
e	1.27 TYPICAL		5, 9
L	5.84	9.14	8
L1	18.93	25.39	
Q	-	1.02	2
S	-	1.40	7

NOTES: See Page 10.

FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)

FIGURE 2(c) - SQUARE CHIP CARRIER PACKAGE, 20 TERMINAL
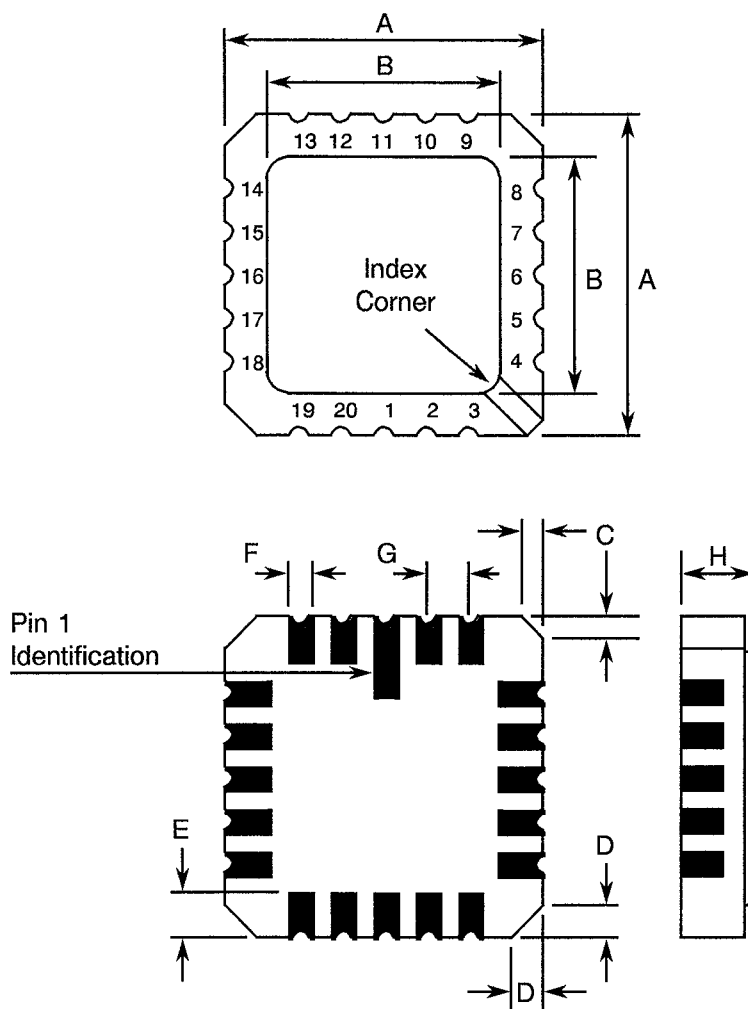
SYMBOL	MILLIMETRES		NOTES
	MIN	MAX	
A	8.69	9.09	
B	7.80	9.09	
C	0.25	0.51	11
D	0.89	1.14	12
E	1.14	1.40	8
F	0.56	0.71	8
G	1.27 TYPICAL		5, 9
H	1.63	2.54	

NOTES: See Page 10.

FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)

NOTES TO FIGURES 2(a) TO 2(c) INCLUSIVE

1. Index area: a notch, letter or dot shall be located adjacent to Pin 1 and shall be within the shaded area shown. For chip carrier packages the index shall be as defined in Figure 2(c).

2. Dimension Q shall be measured at the point of exit of the lead from the body.

3. The dimension shall be measured from the seating plane to the base plane.

4. The dimension allows for off-centre lids, meniscus and glass overrun.

5. The true position pin or terminal spacing is 1.27mm between centrelines. Each pin or terminal centreline shall be located within ±0.13mm of its true longitudinal position relative to Pin 1 and the highest pin number.

6. The true position pin spacing is 2.54mm between centrelines. Each pin centreline shall be located within ±0.25mm of its true longitudinal position relative to Pin 1 and the highest pin number.

7. Applies to all 4 corners.

8. All leads or terminals.

9. 18 spaces for flat and dual-in-line packages.

   16 spaces for chip carrier packages.

10. Lead centreline when α is 0°.

11. Index corner only - 2 dimensions.

12. 3 non-index corners - 6 dimensions.

FIGURE 3(a) - PIN ASSIGNMENT

DUAL-IN-LINE AND FLAT PACKAGE

$1\overline{G}$	1	20	V_{DD}
1A1	2	19	$2\overline{G}$
2Y4	3	18	1Y1
1A2	4	17	2A4
2Y3	5	16	1Y2
1A3	6	15	2A3
2Y2	7	14	1Y3
1A4	8	13	2A2
2Y1	9	12	1Y4
V_{SS}	10	11	2A1
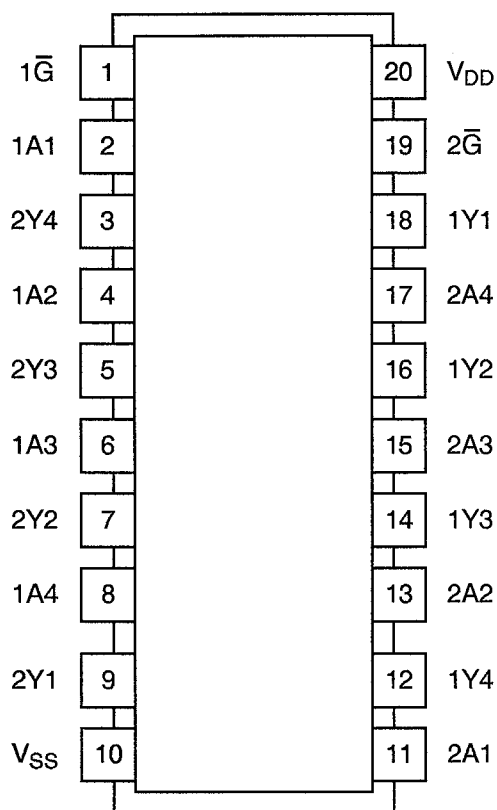
TOP VIEW

CHIP CARRIER PACKAGE

Top edge (pins 18–14): 1Y1, 2A4, 1Y2, 2A3, 1Y3

Left side:
- $2\overline{G}$ 19
- V_{DD} 20
- $1\overline{G}$ 1
- 1A1 2
- 2Y4 3

Right side:
- 13 2A2
- 12 1Y4
- 11 2A1
- 10 V_{SS}
- 9 2Y1

Bottom edge (pins 4–8): 1A2, 2Y3, 1A3, 2Y2, 1A4
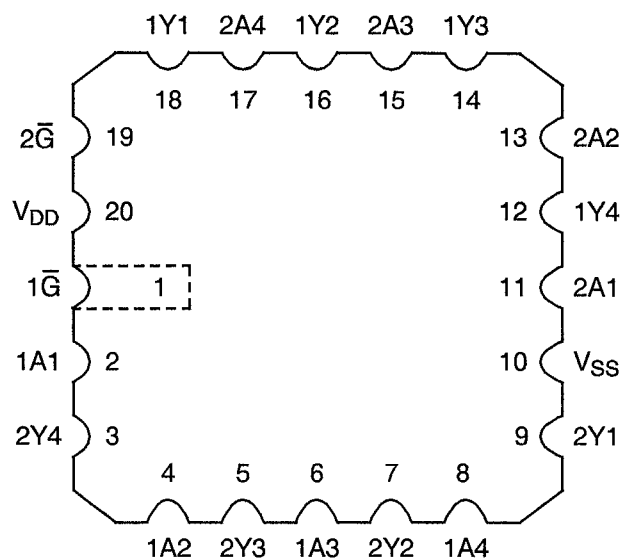
TOP VIEW

FIGURE 3(b) - TRUTH TABLE (EACH BUFFER)

INPUTS		OUTPUT
$\overline{G}$	A	1Y
L	H	L
L	L	H
H	X	Z

NOTES

1. Logic Level Definitions: L = Low Level, H = High Level, Z = High Impedance, X = Irrelevant.

FIGURE 3(c) - CIRCUIT SCHEMATIC

Not applicable.

FIGURE 3(d) - FUNCTIONAL DIAGRAM

Signal	Pin	Block	Out Pin	Output
1Ḡ	(1)	EN		
1A1	(2)	▷ ▽	(18)	1Y1
1A2	(4)		(16)	1Y2
1A3	(6)		(14)	1Y3
1A4	(8)		(12)	1Y4
2Ḡ	(19)	EN		
2A1	(11)	▷ ▽	(9)	2Y1
2A2	(13)		(7)	2Y2
2A3	(15)		(5)	2Y3
2A4	(17)		(3)	2Y4
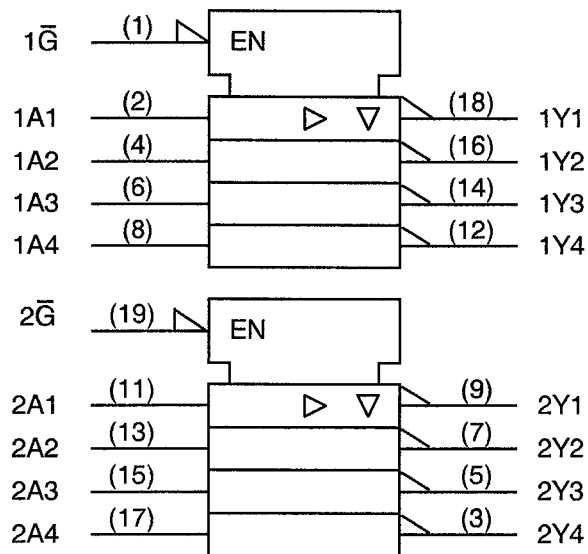
FIGURE 3(e) - INPUT AND OUTPUT PROTECTION NETWORKS

INPUT PROTECTION   OUTPUT PROTECTION

Input O——→ To Gate, with diodes to V_{DD} and ground.

Output O, with diodes to V_{DD} and ground.

2. APPLICABLE DOCUMENTS

The following documents form part of this specification and shall be read in conjunction with it:-

(a) ESA/SCC Generic Specification No. 9000 for Integrated Circuits.

(b) MIL-STD-883, Test Methods and Procedures for Micro-electronics.

3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply. In addition, the following abbreviations are used:

V_{IC} = Input Clamp Voltage.
I_{IC} = Input Clamp Diode Current.
V_{OLP} = Ground Bounce Outputs Low.
V_{OHV} = Ground Bounce Outputs High.

4. REQUIREMENTS

4.1 GENERAL

The complete requirements for procurement of the integrated circuits specified herein are stated in this specification and ESA/SCC Generic Specification No. 9000 for Integrated Circuits. Deviations from the Generic Specification, applicable to this specification only, are listed in Para. 4.2.

Deviations from the applicable Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESA/SCC requirements and do not affect the components' reliability, are listed in the appendices attached to this specification.

4.2 DEVIATIONS FROM GENERIC SPECIFICATION

4.2.1 Deviations from Special In-process Controls

(a) Para. 5.2.2, Total Dose Irradiation Testing: Shall be performed during qualification and maintenance of qualification.

(b) Para. 5.2.2, Total Dose Irradiation Testing: If specified in a Purchase Order, shall be performed during procurement on a lot acceptance basis at the total dose irradiation level specified in the Purchase Order.

4.2.2 Deviations from Final Production Tests (Chart II)

None.

4.2.3 Deviations from Burn-in Tests (Chart III)

None.

4.2.4 Deviations from Qualification Tests (Chart IV)

None.

4.2.5   Deviations from Lot Acceptance Tests (Chart V)

None.

4.3   MECHANICAL REQUIREMENTS

4.3.1   Dimension Check

The dimensions of the integrated circuits specified herein shall be checked. They shall conform to those shown in Figure 2.

4.3.2   Weight

The maximum weight of the integrated circuits specified herein shall be 3.2 grammes for the dual-in-line package, 0.9 grammes for the flat package and 0.6 grammes for the chip carrier package.

4.4   MATERIALS AND FINISHES

The materials shall be as specified herein. Where a definite material is not specified, a material which will enable the integrated circuits specified herein to meet the performance requirements of this specification shall be used. Acceptance or approval of any constituent material does not guarantee acceptance of the finished product.

4.4.1   Case

The case shall be hermetically sealed and have a metal body with hard glass seals or a ceramic body and the lids shall be welded, brazed, preform-soldered or glass frit sealed.

4.4.2   Lead Material and Finish

For dual-in-line and flat packages, the material shall be Type 'G' with Type '4' finish in accordance with the requirements of ESA/SCC Basic Specification No. 23500. For chip carrier packages the finish shall be Type '2' or Type '4' in accordance with the requirements of ESA/SCC Basic Specification No. 23500. (See Table 1(a) for Type Variants).

4.5   MARKING

4.5.1   General

The marking of all components delivered to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 21700. Each component shall be marked in respect of:-

(a) Lead Identification.

(b) The SCC Component Number.

(c) Traceability Information.

4.5.2   Lead Identification

For dual-in-line and flat packages, an index shall be located at the top of the package in the position defined in Note 1 to Figure 2 or, alternatively, a tab may be used to identify Pin No. 1. The pin numbering must be read with the index or tab on the left-hand side. For chip carrier packages, the index shall be as defined by Figure 2(c).

4.5.3   The SCC Component Number

Each component shall bear the SCC Component Number which shall be constituted and marked as follows:

940104201BF

Detail Specification Number ————————————————————————
Type Variant (see Table 1(a)) ————————————————————
Testing Level (B or C, as applicable) ——————————————
Total Dose Irradiation Level (if applicable) ——————————

The Total Dose Irradiation Level designation shall be added for those devices for which a sample has been successfully tested to the level in question. For these devices, a code letter shall be added in accordance with the requirements of ESA/SCC Basic Specification No. 22900.

4.5.4   Traceability Information

Each component shall be marked in respect of traceability information in accordance with the requirements of ESA/SCC Basic Specification No. 21700.

4.6   ELECTRICAL MEASUREMENTS

4.6.1   Electrical Measurements at Room Temperature

The parameters to be measured in respect of electrical characteristics are scheduled in Table 2. Unless otherwise specified, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.6.2   Electrical Measurements at High and Low Temperatures

The parameters to be measured at high and low temperatures are scheduled in Table 3. The measurements shall be performed at $T_{amb} = +125(+0-5)$ °C and $-55(+5-0)$ °C respectively.

4.6.3   Circuits for Electrical Measurements

Circuits and test sequences for use in performing electrical measurements listed in Tables 2 and 3 of this specification are shown in Figure 4.

4.7   BURN-IN TESTS

4.7.1   Parameter Drift Values

The parameter drift values applicable to H.T.R.B. and Power Burn-in are specified in Table 4 of this specification. Unless otherwise stated, measurements shall be performed at $T_{amb} = +22 \pm 3$ °C. The parameter drift values (Δ), applicable to the parameters scheduled, shall not be exceeded. In addition to these drift value requirements, the appropriate limit value specified for a given parameter in Table 2 shall not be exceeded.

For H.T.R.B. Burn-in, the parameter drift values (Δ) shall be applied before the N-Channel (0 hours) and after the P-Channel (144 hours) burn-in.

4.7.2   Conditions for H.T.R.B. and Power Burn-in

The requirements for H.T.R.B. and Power Burn-in are specified in Section 7 of ESA/SCC Generic Specification No. 9000. The conditions for H.T.R.B. and Power Burn-in shall be as specified in Tables 5(a), 5(b) and 5(c) of this specification.

4.7.3   Electrical Circuits for H.T.R.B. and Power Burn-in

Circuits for use in performing the H.T.R.B. and Power Burn-in tests are shown in Figures 5(a), 5(b) and 5(c) of this specification.

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - d.c. PARAMETERS

No.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS MIN	LIMITS MAX	UNIT
1	Functional Test 1	-	-	3(b)	Verify Truth Table with Load. $V_{IL} = 0.45V$, $V_{IH} = 2.5V$ $I_{OL} = 1.0mA$, $I_{OH} = -1.0mA$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ $t_r = t_f < 100ns$ $f = 10kHz$ (min.) Note 1	-	-	-
2	Functional Test 2	-	-	3(b)	Verify Truth Table with Load. $V_{IL} = 0.6V$, $V_{IH} = 3.7V$ $I_{OL} = 1.0mA$, $I_{OH} = -1.0mA$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ $t_r = t_f < 50ns$ $f = 10kHz$ (min.) Note 1	-	-	-
3	Functional Test 3	-	-	3(b)	Verify Truth Table with Load. $V_{IL} = 1.0V$, $V_{IH} = 4.5V$ $I_{OL} = 1.0mA$, $I_{OH} = -1.0mA$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ $t_r = t_f < 50ns$ $f = 10kHz$ (min.) Note 1	-	-	-
4 to 7	Quiescent Current	I_{DD}	3005	4(a)	$V_{IL} = 0V$, $V_{IH} = 5.5V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ All Outputs Open Note 2 (Pin 20)	-	1.0	μA
8 to 17	Input Current Low Level	I_{IL}	3009	4(b)	V_{IN} (Under Test) = 0V V_{IN} (Remaining Inputs) = 5.5V $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 1-2-4-6-8-11-13-15-17-19)	-	-100	nA
18 to 27	Input Current High Level	I_{IH}	3010	4(c)	V_{IN} (Under Test) = 5.5V V_{IN} (Remaining Inputs) = 0V $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 1-2-4-6-8-11-13-15-17-19)	-	100	nA

NOTES: See Page 19.

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - d.c. PARAMETERS (CONT'D)

No.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
28 to 35	Output Voltage Low Level 1	V_{OL1}	3007	4(d)	Buffer Under Test: $V_{IN} = 2.1V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OL} = 50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.1	V
36 to 43	Output Voltage Low Level 2	V_{OL2}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.15V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OL} = 50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.1	V
44 to 51	Output Voltage Low Level 3	V_{OL3}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.85V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OL} = 50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.1	V
52 to 59	Output Voltage Low Level 4	V_{OL4}	3007	4(d)	Buffer Under Test: $V_{IN} = 2.1V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OL} = 12mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.4	V
60 to 67	Output Voltage Low Level 5	V_{OL5}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.15V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OL} = 24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.4	V
68 to 75	Output Voltage Low Level 6	V_{OL6}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.85V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OL} = 24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.4	V

NOTES: See Page 19.

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - d.c. PARAMETERS (CONT'D)

No.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
76 to 83	Output Voltage Low Level 7	V_{OL7}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.85V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OL} = 50mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ Note 3 (Pins 3-5-7-9-12-14-16-18)	-	1.65	V
84 to 91	Output Voltage High Level 1	V_{OH1}	3006	4(e)	Buffer Under Test: $V_{IN} = 0.9V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OH} = -50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	2.9	-	V
92 to 99	Output Voltage High Level 2	V_{OH2}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.35V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OH} = -50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	4.4	-	V
100 to 107	Output Voltage High Level 3	V_{OH3}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.65V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OH} = -50mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	5.4	-	V
108 to 115	Output Voltage High Level 4	V_{OH4}	3006	4(e)	Buffer Under Test: $V_{IN} = 0.9V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OH} = -4.0mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	2.4	-	V
116 to 123	Output Voltage High Level 5	V_{OH5}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.35V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OH} = -24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	3.7	-	V

NOTES: See Page 19.

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - d.c. PARAMETERS (CONT'D)

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
124 to 131	Output Voltage High Level 6	V_{OH6}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.65V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OH} = -24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	4.7	-	V
132 to 139	Output Voltage High Level 7	V_{OH7}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.65V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OH} = -50mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ Note 3 (Pins 3-5-7-9-12-14-16-18)	3.85	-	V
140 to 149	Input Clamp Voltage (to V_{SS})	V_{IC1}	3022	4(f)	I_{IN} (Under Test) $= -1.0mA$ $V_{DD} = $ Open, $V_{SS} = 0V$ All Other Pins Open (Pins 1-2-4-6-8-11-13-15-17-19)	-0.4	-1.5	V
150 to 159	Input Clamp Voltage (to V_{DD})	V_{IC2}	3022	4(f)	I_{IN} (Under Test) $= 1.0mA$ $V_{DD} = 0V$, $V_{SS} = $ Open All Other Pins Open (Pins 1-2-4-6-8-11-13-15-17-19)	0.4	1.5	V
160 to 167	Output Leakage Current Third State (Low Level Applied)	I_{OZL}	3006	4(g)	$V_{IN}(\overline{G}) = 5.5V$ V_{IN}(Remaining Inputs) $= 0V$ $V_{OUT} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	-0.5	µA
168 to 175	Output Leakage Current Third State (High Level Applied)	I_{OZH}	3006	4(g)	$V_{IN}(\overline{G}) = 5.5V$ V_{IN}(Remaining Inputs) $= 0V$ $V_{OUT} = 5.5V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.5	µA

NOTES

1. Maximum time to output comparator strobe 30µs.
2. Test each pattern of Figure 4(a).
3. No more than one output shall be measured at a time and the duration of the test shall not exceed 2.0ms.
4. Guaranteed but not tested.
5. Measurements shall be performed on a 100% basis go-no-go, with read and record on a sample basis, LTPD7 (32 pieces) after Chart III (Burn-in) Tests.
6. Hand test on 5 samples to be performed during Qualification and Extension of Qualification only.

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - a.c. PARAMETERS

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
176 to 185	Input Capacitance	C_{IN}	3012	4(h)	V_{IN} (Not Under Test) = 0V $V_{DD} = V_{SS} = 0V$ Note 4 (Pins 1-2-4-6-8-11-13-15-17-19)	-	8.0	pF
186	Propagation Delay Low to High (1A1 to 1Y1)	t_{PLH}	3003	4(i)	Buffer Under Test: V_{IN} = Pulse Generator $V_{IN}(1\overline{G}) = 1.35V$ V_{IN} (Remaining Inputs) = 0V $V_{DD} = 4.5V$, $V_{SS} = 0V$ Note 5 Pins 2 to 18	-	6.5	ns
187	Propagation Delay High to Low (1A1 to 1Y1)	t_{PHL}	3003	4(i)	Buffer Under Test: V_{IN} = Pulse Generator $V_{IN}(1\overline{G}) = 1.35V$ V_{IN} (Remaining Inputs) = 0V $V_{DD} = 4.5V$, $V_{SS} = 0V$ Note 5 Pins 2 to 18	-	6.0	ns
188	Output Enable Time High Impedance to Low Output (2$\overline{G}$ to 2Y1)	t_{PZL}	3003	4(i)	$V_{IN}(2\overline{G})$ = Pulse Generator $V_{IN}(2A1) = 3.15V$ V_{IN} (Remaining Inputs) = 0V $V_{DD} = 4.5V$, $V_{SS} = 0V$ Note 5 Pins 19 to 9	-	8.0	ns
189	Output Enable Time High Impedance to High Output (2$\overline{G}$ to 2Y1)	t_{PZH}	3003	4(i)	$V_{IN}(2\overline{G})$ = Pulse Generator $V_{IN}(2A1) = 1.35V$ V_{IN} (Remaining Inputs) = 0V $V_{DD} = 4.5V$, $V_{SS} = 0V$ Note 5 Pins 19 to 9	-	7.0	ns

NOTES: See Page 19.

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - a.c. PARAMETERS (CONT'D)

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
190	Output Disable Time Low Output to High Impedance (2$\overline{G}$ to 2Y1)	t_{PLZ}	3003	4(i)	$V_{IN}(2\overline{G})$ = Pulse Generator $V_{IN}(2A1)$ = 3.15V V_{IN} (Remaining Inputs) = 0V V_{DD} = 4.5V, V_{SS} = 0V Note 5 Pins 19 to 9	-	9.0	ns
191	Output Disable Time High Output to High Impedance (2$\underline{G}$ to 2Y1)	t_{PHZ}	3003	4(i)	$V_{IN}(2\overline{G})$ = Pulse Generator $V_{IN}(2A1)$ = 1.35V V_{IN} (Remaining Inputs) = 0V V_{DD} = 4.5V, V_{SS} = 0V Note 5 Pins 19 to 9	-	8.5	ns
192	Ground Bounce Output Low (High to Low)	$V_{OLP(H-L)}$	-	4(j)	V_{IN} (1$\overline{G}$, 2$\overline{G}$) = 1.0V V_{IN} (1A1) = 4.0V V_{IN} (Remaining Inputs) = Pulse Generator V_{DD} = 5.5V, V_{SS} = 0V Note 6 (Pin 18)	-	2.5	V
193	Ground Bounce Output Low (Low to High)	$V_{OLP(L-H)}$	-	4(j)	V_{IN} (1$\overline{G}$, 2$\overline{G}$) = 1.0V V_{IN} (1A1) = 4.0V V_{IN} (Remaining Inputs) = Pulse Generator V_{DD} = 5.5V, V_{SS} = 0V Note 6 (Pin 18)	-	2.5	V
194	Ground Bounce Output High (High to Low)	$V_{OHV(H-L)}$	-	4(j)	V_{IN} (1A1, 1$\overline{G}$, 2$\overline{G}$) = 1.0V V_{IN} (Remaining Inputs) = Pulse Generator V_{DD} = 5.5V, V_{SS} = 0V Note 6 (Pin 18)	-	2.0	V
195	Ground Bounce Output High (Low to High)	$V_{OHV(L-H)}$	-	4(j)	V_{IN} (1A1, 1$\overline{G}$, 2$\overline{G}$) = 1.0V V_{IN} (Remaining Inputs) = Pulse Generator V_{DD} = 5.5V, V_{SS} = 0V Note 6 (Pin 18)	-	2.0	V

NOTES: See Page 19.

TABLE 3(a) - ELECTRICAL MEASUREMENTS AT HIGH TEMPERATURE

No.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS MIN	LIMITS MAX	UNIT
1	Functional Test 1	-	-	3(b)	Verify Truth Table with Load. $V_{IL} = 0.45V$, $V_{IH} = 2.5V$ $I_{OL} = 1.0mA$, $I_{OH} = -1.0mA$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ $t_r = t_f < 100ns$ $f = 10kHz$ (min.) Note 1	-	-	-
2	Functional Test 2	-	-	3(b)	Verify Truth Table with Load. $V_{IL} = 0.6V$, $V_{IH} = 3.7V$ $I_{OL} = 1.0mA$, $I_{OH} = -1.0mA$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ $t_r = t_f < 50ns$ $f = 10kHz$ (min.) Note 1	-	-	-
3	Functional Test 3			3(b)	Verify Truth Table with Load. $V_{IL} = 1.0V$, $V_{IH} = 4.5V$ $I_{OL} = 1.0mA$, $I_{OH} = -1.0mA$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ $t_r = t_f < 50ns$ $f = 10kHz$ (min.) Note 1	-	-	-
4 to 7	Quiescent Current	I_{DD}	3005	4(a)	$V_{IL} = 0V$, $V_{IH} = 5.5V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ All Outputs Open Note 2 (Pin 20)	-	20	µA
8 to 17	Input Current Low Level	I_{IL}	3009	4(b)	V_{IN} (Under Test) $= 0V$ V_{IN} (Remaining Inputs) $= 5.5V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 1-2-4-6-8-11-13-15-17-19)	-	-1.0	µA
18 to 27	Input Current High Level	I_{IH}	3010	4(c)	V_{IN} (Under Test) $= 5.5V$ V_{IN} (Remaining Inputs) $= 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 1-2-4-6-8-11-13-15-17-19)	-	1.0	µA

NOTES: See Page 19.

TABLE 3(a) - ELECTRICAL MEASUREMENTS AT HIGH TEMPERATURE (CONT'D)

No.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
28 to 35	Output Voltage Low Level 1	V_{OL1}	3007	4(d)	Buffer Under Test: $V_{IN} = 2.1V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OL} = 50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.1	V
36 to 43	Output Voltage Low Level 2	V_{OL2}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.15V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OL} = 50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.1	V
44 to 51	Output Voltage Low Level 3	V_{OL3}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.85V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OL} = 50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.1	V
52 to 59	Output Voltage Low Level 4	V_{OL4}	3007	4(d)	Buffer Under Test: $V_{IN} = 2.1V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OL} = 12mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.5	V
60 to 67	Output Voltage Low Level 5	V_{OL5}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.15V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OL} = 24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.5	V
68 to 75	Output Voltage Low Level 6	V_{OL6}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.85V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OL} = 24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.5	V

NOTES: See Page 19.

TABLE 3(a) - ELECTRICAL MEASUREMENTS AT HIGH TEMPERATURE (CONT'D)

No.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
76 to 83	Output Voltage Low Level 7	V_{OL7}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.85V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OL} = 50mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ Note 3 (Pins 3-5-7-9-12-14-16-18)	-	1.65	V
84 to 91	Output Voltage High Level 1	V_{OH1}	3006	4(e)	Buffer Under Test: $V_{IN} = 0.9V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OH} = -50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	2.9	-	V
92 to 99	Output Voltage High Level 2	V_{OH2}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.35V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OH} = -50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	4.4	-	V
100 to 107	Output Voltage High Level 3	V_{OH3}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.65V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OH} = -50mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	5.4	-	V
108 to 115	Output Voltage High Level 4	V_{OH4}	3006	4(e)	Buffer Under Test: $V_{IN} = 0.9V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OH} = -4.0mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	2.4	-	V
116 to 123	Output Voltage High Level 5	V_{OH5}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.35V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OH} = -24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	3.7	-	V

NOTES: See Page 19.

TABLE 3(a) - ELECTRICAL MEASUREMENTS AT HIGH TEMPERATURE (CONT'D)

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
124 to 131	Output Voltage High Level 6	V_{OH6}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.65V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OH} = -24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	4.7	-	V
132 to 139	Output Voltage High Level 7	V_{OH7}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.65V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OH} = -50mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ Note 3 (Pins 3-5-7-9-12-14-16-18)	3.85	-	V
140 to 149	Input Clamp Voltage (to V_{SS})	V_{IC1}	3022	4(f)	I_{IN} (Under Test) = $-1.0mA$ $V_{DD} =$ Open, $V_{SS} = 0V$ All Other Pins Open (Pins 1-2-4-6-8-11-13-15-17-19)	-0.1	-1.5	V
150 to 159	Input Clamp Voltage (to V_{DD})	V_{IC2}	3022	4(f)	I_{IN} (Under Test) = 1.0mA $V_{DD} = 0V$, $V_{SS} =$ Open All Other Pins Open (Pins 1-2-4-6-8-11-13-15-17-19)	0.1	1.5	V
160 to 167	Output Leakage Current Third State (Low Level Applied)	I_{OZL}	3006	4(g)	$V_{IN}(\overline{G}) = 5.5V$ V_{IN}(Remaining Inputs) = 0V $V_{OUT} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	-10	µA
168 to 175	Output Leakage Current Third State (High Level Applied)	I_{OZH}	3006	4(g)	$V_{IN}(\overline{G}) = 5.5V$ V_{IN}(Remaining Inputs) = 0V $V_{OUT} = 5.5V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	10	µA

NOTES: See Page 19.

TABLE 3(b) - ELECTRICAL MEASUREMENTS AT LOW TEMPERATURE

No.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
1	Functional Test 1	-	-	3(b)	Verify Truth Table with Load. $V_{IL} = 0.45V$, $V_{IH} = 2.5V$ $I_{OL} = 1.0mA$, $I_{OH} = -1.0mA$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ $t_r = t_f < 100ns$ $f = 10kHz$ (min.) Note 1	-	-	-
2	Functional Test 2	-	-	3(b)	Verify Truth Table with Load. $V_{IL} = 0.6V$, $V_{IH} = 3.7V$ $I_{OL} = 1.0mA$, $I_{OH} = -1.0mA$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ $t_r = t_f < 50ns$ $f = 10kHz$ (min.) Note 1	-	-	-
3	Functional Test 3	-	-	3(b)	Verify Truth Table with Load. $V_{IL} = 1.0V$, $V_{IH} = 4.5V$ $I_{OL} = 1.0mA$, $I_{OH} = -1.0mA$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ $t_r = t_f < 50ns$ $f = 10kHz$ (min.) Note 1	-	-	-
4 to 7	Quiescent Current	I_{DD}	3005	4(a)	$V_{IL} = 0V$, $V_{IH} = 5.5V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ All Outputs Open Note 2 (Pin 20)	-	1.0	μA
8 to 17	Input Current Low Level	I_{IL}	3009	4(b)	V_{IN} (Under Test) = 0V V_{IN} (Remaining Inputs) = 5.5V $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 1-2-4-6-8-11-13-15-17-19)	-	-100	nA
18 to 27	Input Current High Level	I_{IH}	3010	4(c)	V_{IN} (Under Test) = 5.5V V_{IN} (Remaining Inputs) = 0V $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 1-2-4-6-8-11-13-15-17-19)	-	100	nA

NOTES: See Page 19.

TABLE 3(b) - ELECTRICAL MEASUREMENTS AT LOW TEMPERATURE (CONT'D)

No.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
28 to 35	Output Voltage Low Level 1	V_{OL1}	3007	4(d)	Buffer Under Test: $V_{IN} = 2.1V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OL} = 50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.1	V
36 to 43	Output Voltage Low Level 2	V_{OL2}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.15V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OL} = 50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.1	V
44 to 51	Output Voltage Low Level 3	V_{OL3}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.85V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OL} = 50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.1	V
52 to 59	Output Voltage Low Level 4	V_{OL4}	3007	4(d)	Buffer Under Test: $V_{IN} = 2.1V$ $V_{IN}(\overline{G}) = 0.9V$ $I_{OL} = 12mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.4	V
60 to 67	Output Voltage Low Level 5	V_{OL5}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.15V$ $V_{IN}(\overline{G}) = 1.35V$ $I_{OL} = 24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.4	V
68 to 75	Output Voltage Low Level 6	V_{OL6}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.85V$ $V_{IN}(\overline{G}) = 1.65V$ $I_{OL} = 24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.4	V

NOTES: See Page 19.

TABLE 3(b) - ELECTRICAL MEASUREMENTS AT LOW TEMPERATURE (CONT'D)

No.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
76 to 83	Output Voltage Low Level 7	V_{OL7}	3007	4(d)	Buffer Under Test: $V_{IN} = 3.85V$ $V_{IN}(\bar{G}) = 1.65V$ $I_{OL} = 50mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ Note 3 (Pins 3-5-7-9-12-14-16-18)	-	1.65	V
84 to 91	Output Voltage High Level 1	V_{OH1}	3006	4(e)	Buffer Under Test: $V_{IN} = 0.9V$ $V_{IN}(\bar{G}) = 0.9V$ $I_{OH} = -50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	2.9	-	V
92 to 99	Output Voltage High Level 2	V_{OH2}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.35V$ $V_{IN}(\bar{G}) = 1.35V$ $I_{OH} = -50\mu A$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	4.4	-	V
100 to 107	Output Voltage High Level 3	V_{OH3}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.65V$ $V_{IN}(\bar{G}) = 1.65V$ $I_{OH} = -50mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	5.4	-	V
108 to 115	Output Voltage High Level 4	V_{OH4}	3006	4(e)	Buffer Under Test: $V_{IN} = 0.9V$ $V_{IN}(\bar{G}) = 0.9V$ $I_{OH} = -4.0mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 3.0V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	2.4	-	V
116 to 123	Output Voltage High Level 5	V_{OH5}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.35V$ $V_{IN}(\bar{G}) = 1.35V$ $I_{OH} = -24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 4.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	3.7	-	V

NOTES: See Page 19.

TABLE 3(b) - ELECTRICAL MEASUREMENTS AT LOW TEMPERATURE (CONT'D)

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST)	LIMITS		UNIT
						MIN	MAX	
124 to 131	Output Voltage High Level 6	V_{OH6}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.65V$ $V_{IN}(\bar{G}) = 1.65V$ $I_{OH} = -24mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	4.7	-	V
132 to 139	Output Voltage High Level 7	V_{OH7}	3006	4(e)	Buffer Under Test: $V_{IN} = 1.65V$ $V_{IN}(\bar{G}) = 1.65V$ $I_{OH} = -50mA$ All Other Inputs: $V_{IN} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ Note 3 (Pins 3-5-7-9-12-14-16-18)	3.85	-	V
140 to 149	Input Clamp Voltage (to V_{SS})	V_{IC1}	3022	4(f)	I_{IN} (Under Test) = $-1.0mA$ $V_{DD} = $ Open, $V_{SS} = 0V$ All Other Pins Open (Pins 1-2-4-6-8-11-13-15-17-19)	-0.1	-1.5	V
150 to 159	Input Clamp Voltage (to V_{DD})	V_{IC2}	3022	4(f)	I_{IN} (Under Test) = 1.0mA $V_{DD} = 0V$, $V_{SS} = $ Open All Other Pins Open (Pins 1-2-4-6-8-11-13-15-17-19)	0.1	1.5	V
160 to 167	Output Leakage Current Third State (Low Level Applied)	I_{OZL}	3006	4(g)	$V_{IN}(\bar{G}) = 5.5V$ V_{IN}(Remaining Inputs) = 0V $V_{OUT} = 0V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	-0.5	μA
168 to 175	Output Leakage Current Third State (High Level Applied)	I_{OZH}	3006	4(g)	$V_{IN}(\bar{G}) = 5.5V$ V_{IN}(Remaining Inputs) = 0V $V_{OUT} = 5.5V$ $V_{DD} = 5.5V$, $V_{SS} = 0V$ (Pins 3-5-7-9-12-14-16-18)	-	0.5	μA

NOTES: See Page 19.

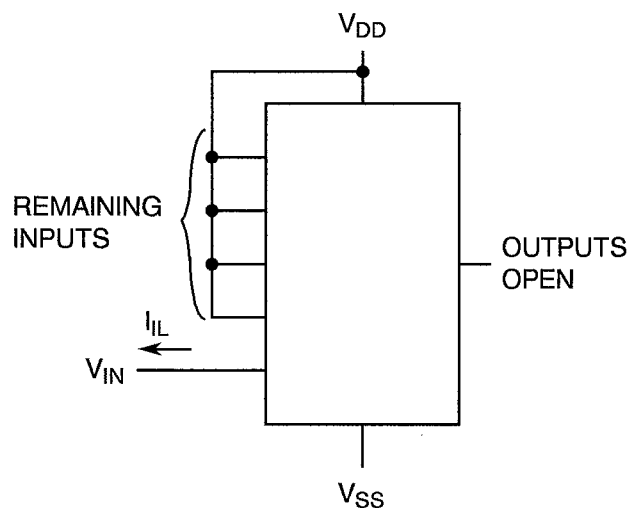## FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS

FIGURE 4(a) - QUIESCENT CURRENT TEST TABLE

PATTERN NO.	INPUTS										OUTPUTS								D.C. SUPPLY	
	1	2	4	6	8	11	13	15	17	19	3	5	7	9	12	14	16	18	10	20
1	0	0	0	0	0	0	0	0	0	0	OPEN								V_{SS}	V_{DD}
2	0	1	1	1	1	1	1	1	1	0	OPEN									
3	1	1	1	1	1	0	0	0	0	0	OPEN									
4	0	0	0	0	0	1	1	1	1	1	OPEN									

NOTES
1. Figure 4(a) illustrates one series of test patterns. Any other pattern series must be agreed with the qualifying Space Agency and shall be included as an Appendix.

2. Logic Level Definitions: $1 = V_{IH} = V_{DD}$, $0 = V_{IL} = V_{SS}$.

FIGURE 4(b) - INPUT CURRENT LOW LEVEL

FIGURE 4(c) - INPUT CURRENT HIGH LEVEL
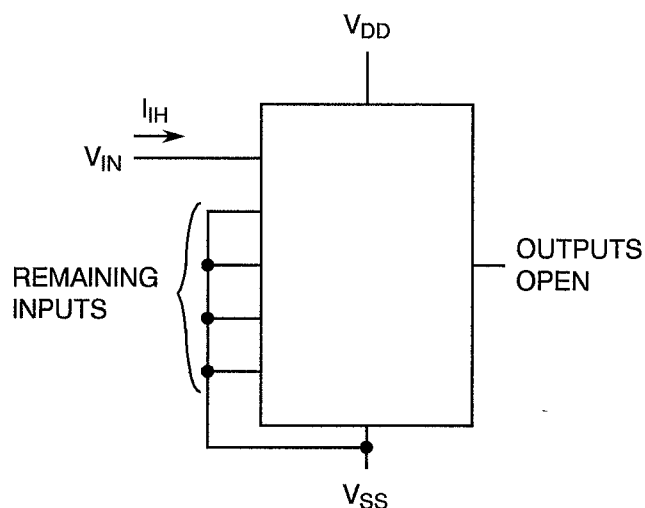
NOTES
1. Each input to be tested separately.

NOTES
1. Each input to be tested separately.

FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS (CONTINUED)

FIGURE 4(d) - OUTPUT VOLTAGE LOW LEVEL
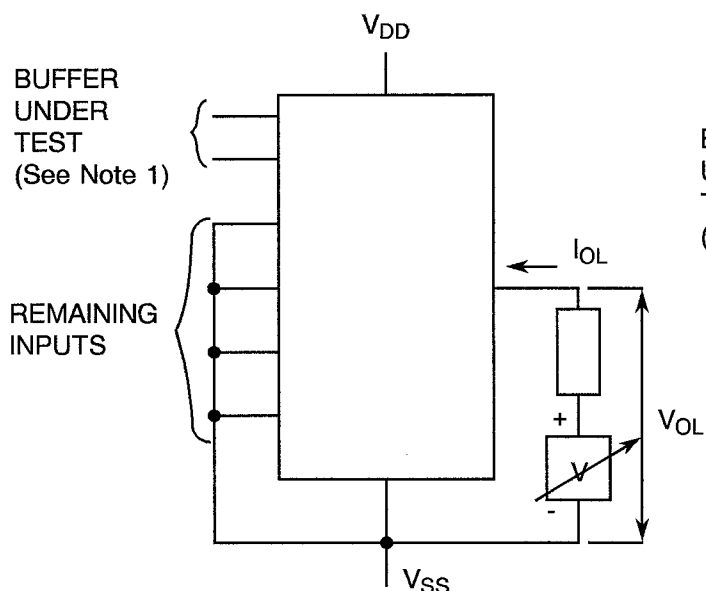
NOTES
1. $V_{IN} = V_{IH}(min)$ with $\bar{G}$ at $V_{IL}(max)$.
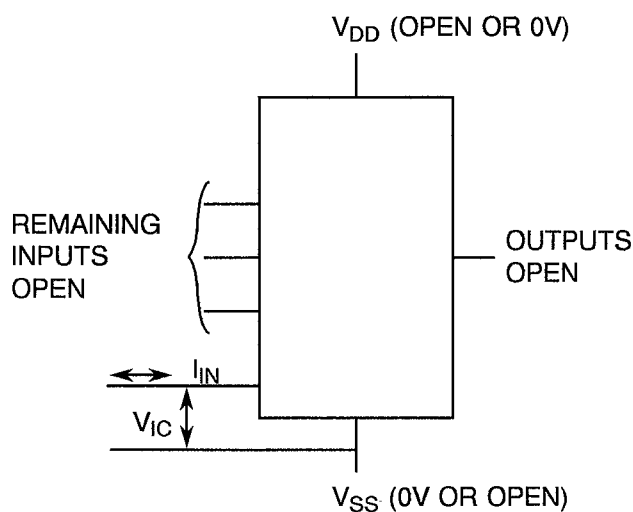2. Each output to be tested separately.

FIGURE 4(e) - OUTPUT VOLTAGE HIGH LEVEL
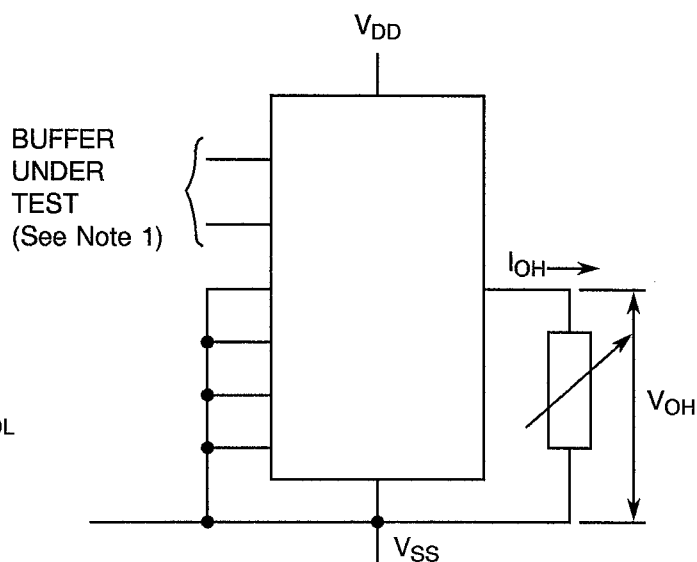
NOTES
1. $V_{IN} = V_{IL}(max)$ with $\bar{G}$ at $V_{IL}(max)$.
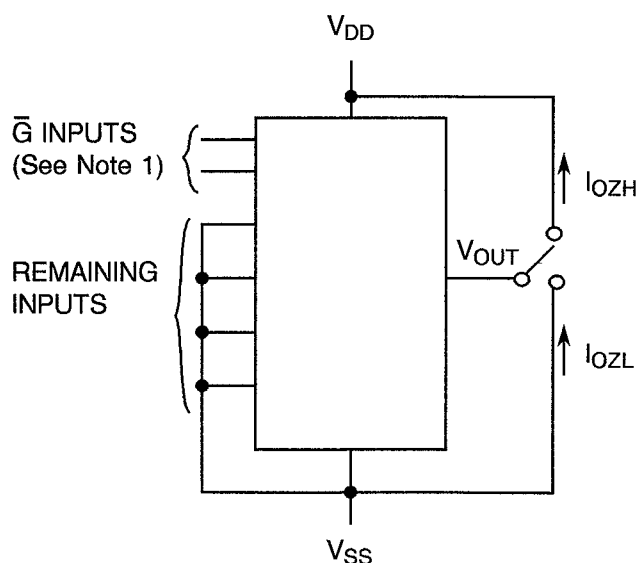2. Each output to be tested separately.

FIGURE 4(f) - INPUT CLAMP VOLTAGE

NOTES
1. Each input to be tested separately.

FIGURE 4(g) - OUTPUT LEAKAGE CURRENT THIRD STATE

NOTES
1. $\bar{G}$ inputs at 5.5V.
2. Each output to be tested separately.

FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS (CONTINUED)
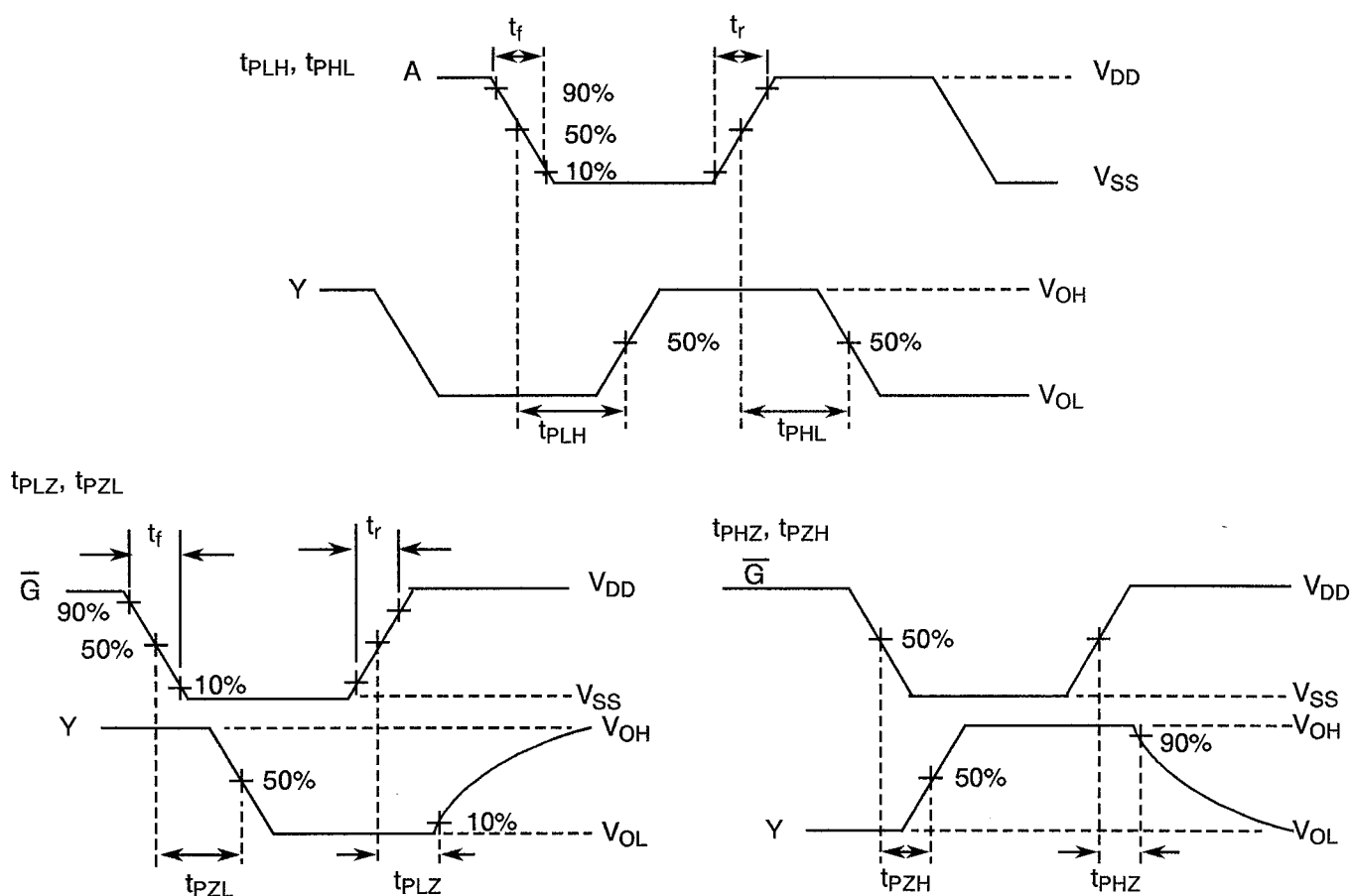
FIGURE 4(h) - INPUT CAPACITANCE
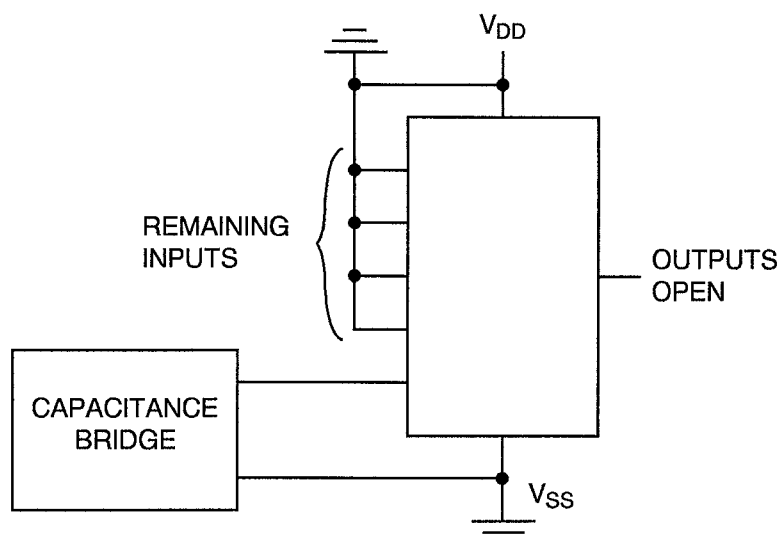
NOTES

1. Each input to be tested separately.

2. $f = 100kHz$ to $1MHz$.

FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS (CONTINUED)

FIGURE 4(i) - PROPAGATION DELAY
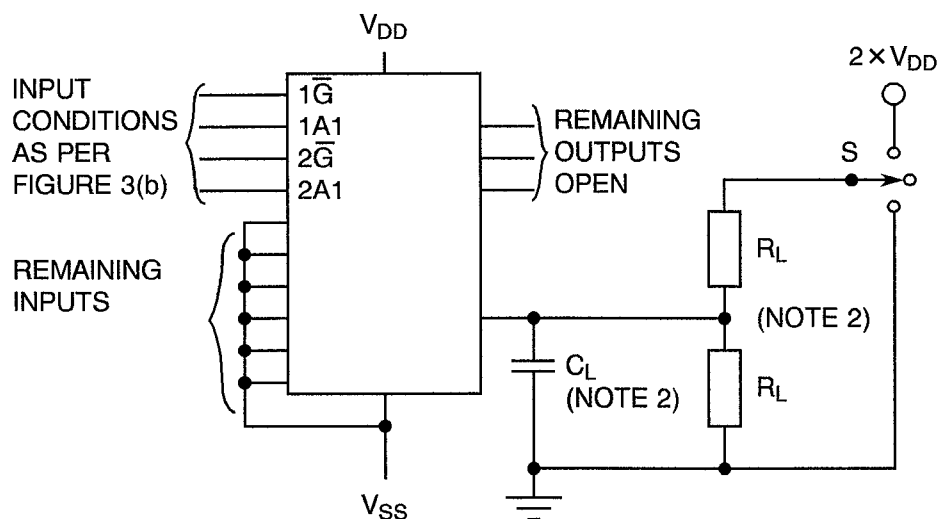
PARAMETER	S
t_{PZH}, t_{PHZ}	Ground
t_{PZL}, t_{PLZ}	$2 \times V_{DD}$
t_{PLH}, t_{PHL}	Open

VOLTAGE WAVEFORMS

NOTES

1. Pulse Generator: $V_p = 0V$ to V_{DD}, t_r and $t_f \leq 6ns$, $f = 1.0MHz$ minimum, 50% Duty Cycle, $Z_{OUT} = 50\Omega$.
2. $C_L = 50pF \pm 5\%$ including scope, wiring and stray capacitance without package in test fixture, $R_L = 500\Omega \pm 5\%$.

FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS (CONTINUED)

FIGURE 4(j) - GROUND BOUNCE
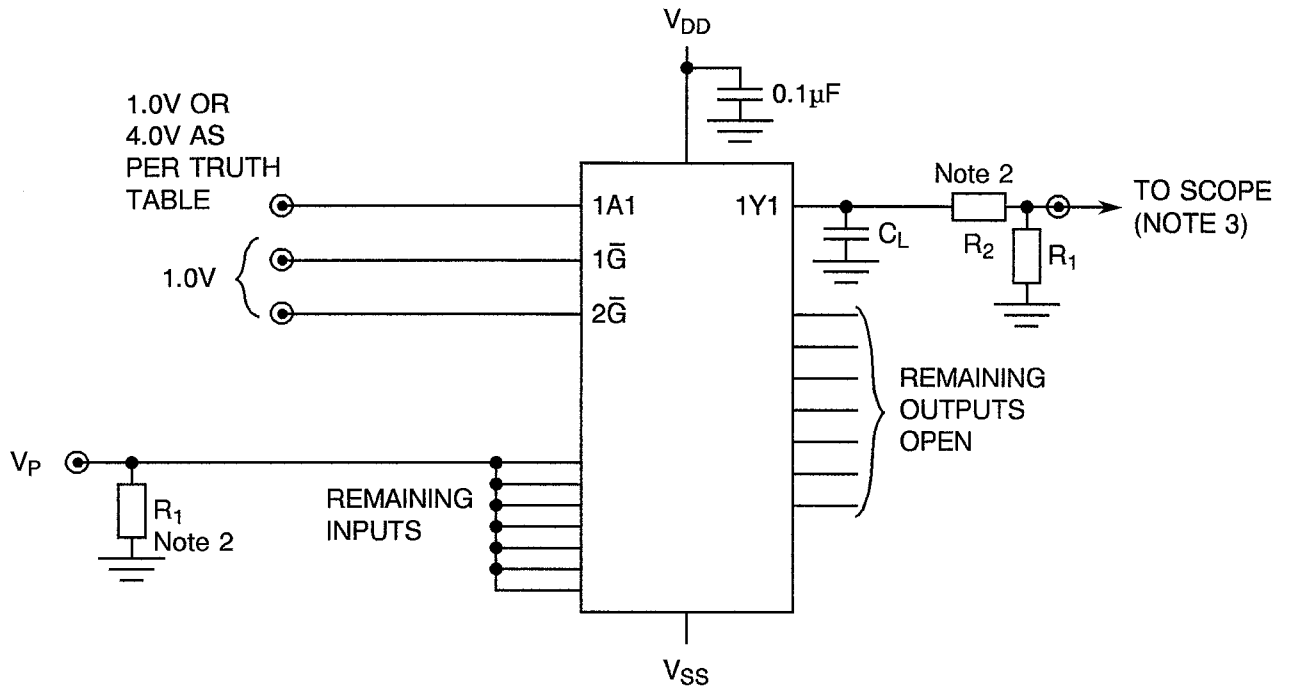
VOLTAGE WAVEFORMS
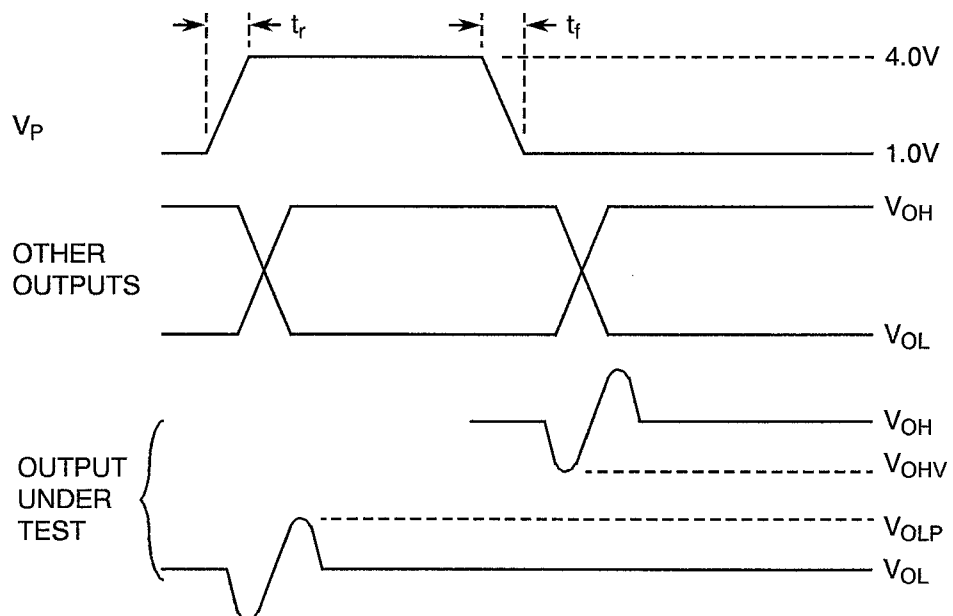
NOTES

1. Pulse Generator - $V_P = 1.0V$ to $4.0V$, t_r and $t_f \leq 6.0ns$, $f = 1.0MHz$, 50% Duty Cycle, $Z_{OUT} = 50\Omega$.

2. $C_L = 50pF \pm 5\%$, $R1 = 51\Omega \pm 5\%$, $R2 = 450\Omega \pm 5\%$.

3. Oscilloscope - $Z_{IN} = 50\Omega$, Bandwidth $\geq 1.0GHz$ with memory capability.

TABLE 4 - PARAMETER DRIFT VALUES

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITIONS	CHANGE LIMITS (Δ)	UNIT
4 to 7	Quiescent Current	I_{DD}	As per Table 2	As per Table 2	± 300	nA
8 to 17	Input Current Low Level	I_{IL}	As per Table 2	As per Table 2	± 20	nA
18 to 27	Input Current High Level	I_{IH}	As per Table 2	As per Table 2	± 20	nA
68 to 75	Output Voltage Low Level 6	V_{OL6}	As per Table 2	As per Table 2	± 0.04	V
124 to 131	Output Voltage High Level 6	V_{OH6}	As per Table 2	As per Table 2	± 0.2	V

TABLE 5(a) - CONDITIONS FOR BURN-IN HIGH TEMPERATURE REVERSE BIAS, N-CHANNELS

No.	CHARACTERISTICS	SYMBOL	CONDITION	UNIT
1	Ambient Temperature	T_{amb}	+125(+0-5)	°C
2	Outputs - (Pins 3-5-7-9-12-14-16-18)	V_{OUT}	Open	-
3	Inputs - (Pins 1-2-4-6-8-11-13-15-17-19)	V_{IN}	V_{SS}	V
4	Positive Supply Voltage (Pin 20)	V_{DD}	5.5(+0-0.5)	V
5	Negative Supply Voltage (Pin 10)	V_{SS}	0	V
6	Duration	t	72	Hours

NOTES
1. Input Protection Resistor = R1 = 1.0kΩ.

2. Output Load = R2 = 10kΩ.

TABLE 5(b) - CONDITIONS FOR BURN-IN HIGH TEMPERATURE REVERSE BIAS, P-CHANNELS

No.	CHARACTERISTICS	SYMBOL	CONDITION	UNIT
1	Ambient Temperature	T_{amb}	+125(+0-5)	°C
2	Outputs - (Pins 3-5-7-9-12-14-16-18)	V_{OUT}	Open	-
3	Inputs - (Pins 1-2-4-6-8-11-13-15-17-19)	V_{IN}	V_{DD}	V
4	Positive Supply Voltage (Pin 20)	V_{DD}	5.5(+0-0.5)	V
5	Negative Supply Voltage (Pin 10)	V_{SS}	0	V
6	Duration	t	72	Hours

NOTES
1. Input Protection Resistor = R1 = 1.0kΩ.

2. Output Load = R2 = 10kΩ.

TABLE 5(c) - CONDITIONS FOR POWER BURN-IN AND OPERATING LIFE TESTS

No.	CHARACTERISTICS	SYMBOL	CONDITIONS	UNIT
1	Ambient Temperature	T_{amb}	$+125(+0-5)$	°C
2	Outputs - (Pins 3-5-7-9-12-14-16-18)	V_{OUT}	$V_{DD}/2$	V
3	Inputs - (Pins 1-19)	V_{IN}	V_{SS}	V
4	Inputs - (Pins 2-4-6-8-11-13-15-17)	V_{IN}	V_{GEN}	Vac
5	Pulse Voltage	V_{GEN}	0V to V_{DD}	Vac
6	Pulse Frequency Square Wave	f	$100k \pm 10\%$ $50 \pm 15\%$ Duty Cycle $t_r = t_f < 100ns$	Hz
7	Positive Supply Voltage (Pin 20)	V_{DD}	$5.5(+0-0.5)$	V
8	Negative Supply Voltage (Pin 10)	V_{SS}	0	V

NOTES
1.   Input Protection Resistor = Output Load = 220Ω.

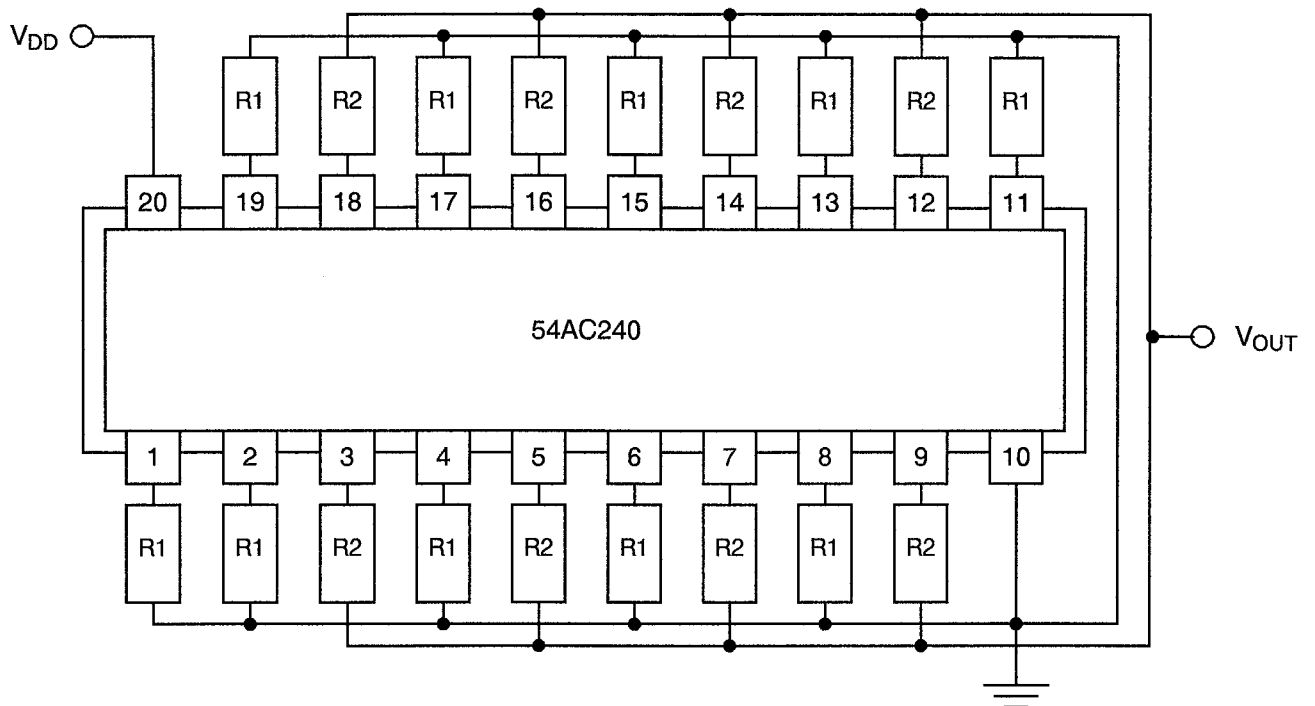**FIGURE 5(a) - ELECTRICAL CIRCUIT FOR BURN-IN HIGH TEMPERATURE REVERSE BIAS, N-CHANNELS**
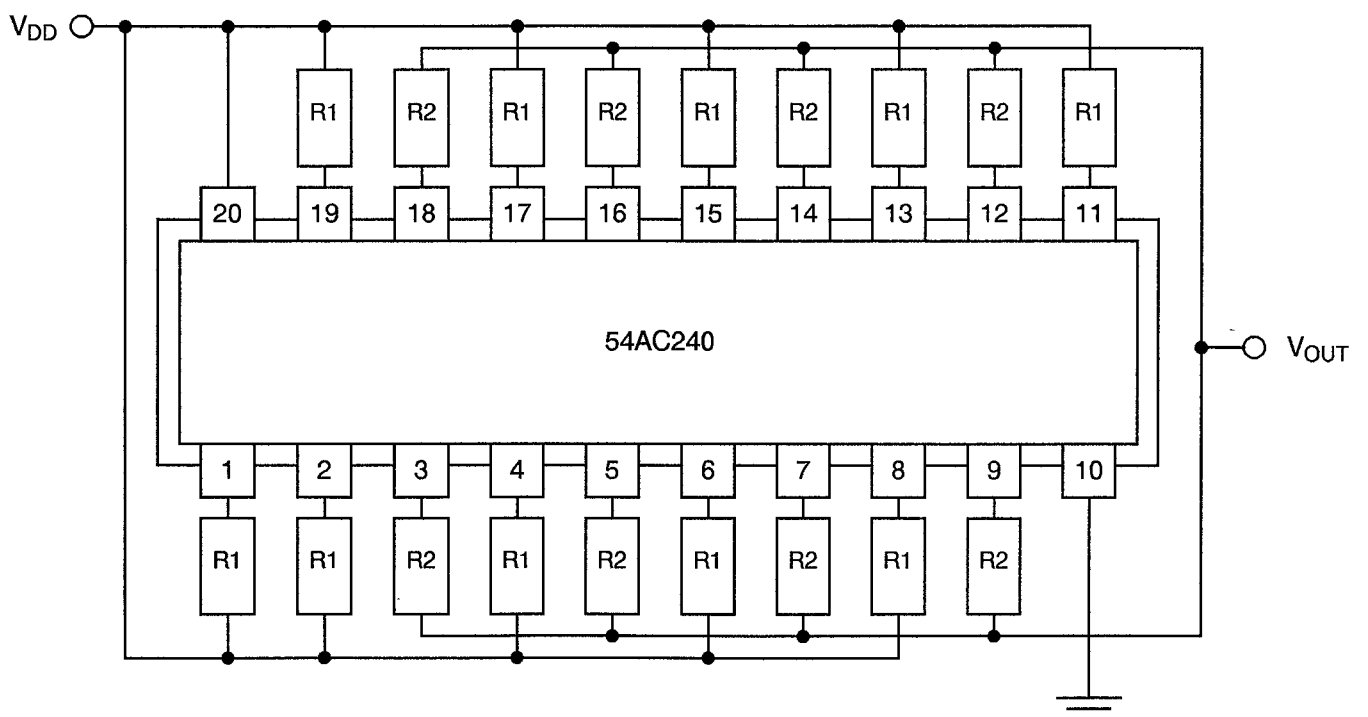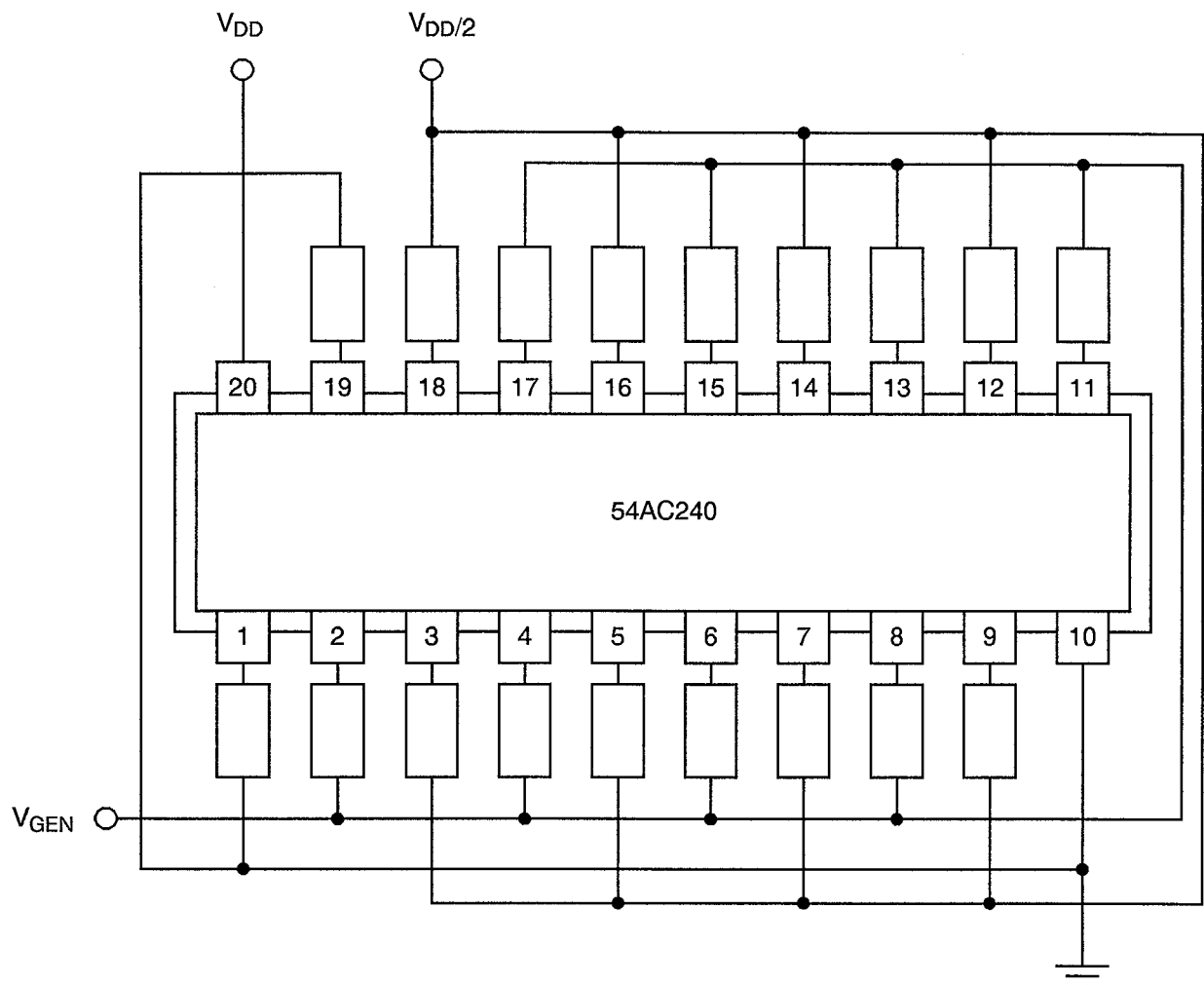

FIGURE 5(b) - ELECTRICAL CIRCUIT FOR BURN-IN HIGH TEMPERATURE REVERSE BIAS, P-CHANNELS

FIGURE 5(c) - ELECTRICAL CIRCUIT FOR POWER BURN-IN AND OPERATING LIFE TESTS

4.8 ENVIRONMENTAL AND ENDURANCE TESTS (CHARTS IV AND V OF ESA/SCC GENERIC SPECIFICATION NO. 9000)

4.8.1 Electrical Measurements on Completion of Environmental Tests

The parameters to be measured on completion of environmental tests are scheduled in Table 6. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.8.2 Electrical Measurements at Intermediate Points during Endurance Tests

The parameters to be measured at intermediate points during endurance testing are as scheduled in Table 6 of this specification. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.8.3 Electrical Measurements on Completion of Endurance Tests

The parameters to be measured on completion of endurance testing are as scheduled in Table 6 of this specification. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.8.4 Conditions for Operating Life Tests

The requirements for operating life testing are specified in Section 9 of ESA/SCC Generic Specification No. 9000. The conditions for operating life testing shall be as specified in Table 5(c) of this specification.

4.8.5 Electrical Circuits for Operating Life Tests

Circuits for use in performing the operating life tests are shown in Figure 5(c) of this specification.

4.8.6 Conditions for High Temperature Storage Test

The requirements for the high temperature storage test are specified in ESA/SCC Generic Specification No. 9000. The temperature to be applied shall be the maximum storage temperature specified in Table 1(b) of this specification.

4.9 TOTAL DOSE IRRADIATION TESTING

4.9.1 Application

If specified in Para. 4.2.1 of this specification, total dose irradiation testing shall be performed in accordance with the requirements of ESA/SCC Basic Specification No. 22900.

4.9.2 Bias Conditions

Continuous bias shall be applied during irradiation testing as shown in Figure 6 of this specification.

4.9.3 Electrical Measurements

The parameters to be measured prior to irradiation exposure are scheduled in Table 2 of this specification. Only devices which meet the requirements of Table 2 shall be included in the test sample.

The parameters to be measured during and on completion of irradiation testing are scheduled in Table 7 of this specification.
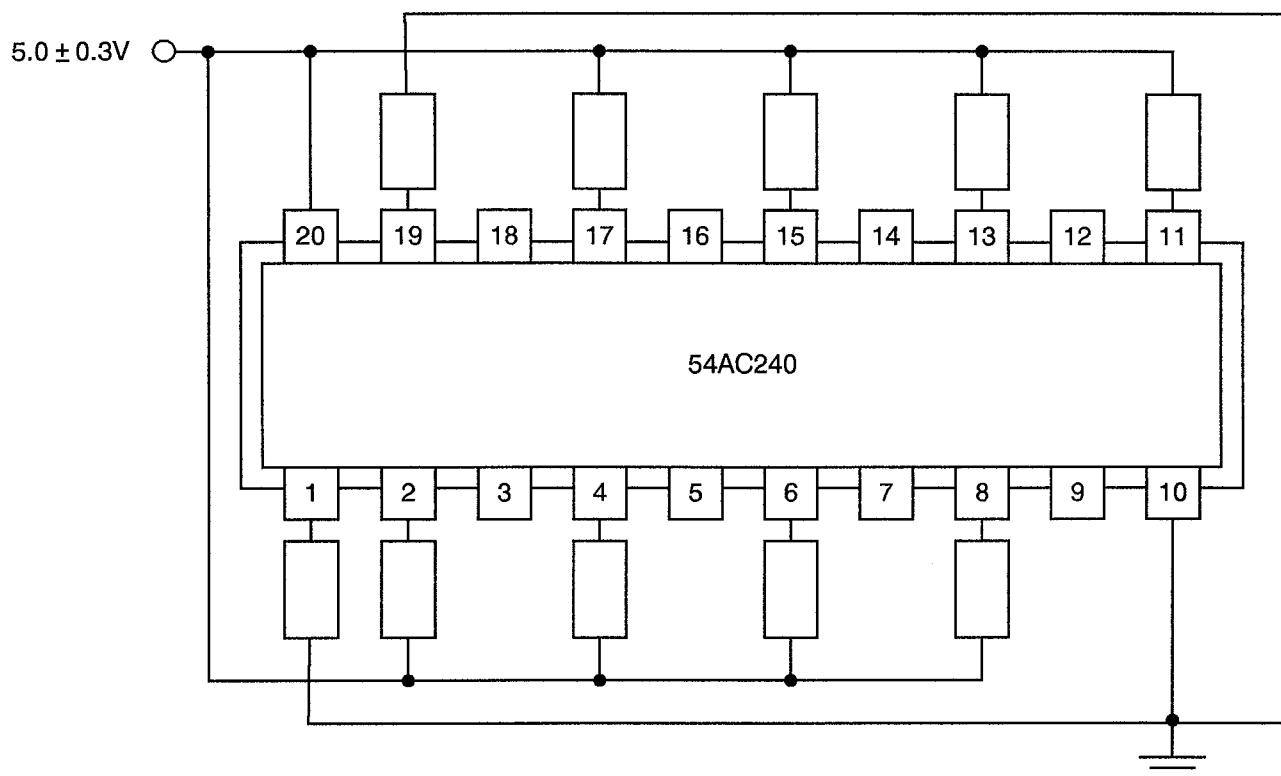
TABLE 6 - ELECTRICAL MEASUREMENTS ON COMPLETION OF ENVIRONMENTAL TESTS AND AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING

NO.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITIONS	CHANGE LIMITS (Δ) NOTE 1	ABSOLUTE		UNIT
						MIN	MAX	
1	Functional Test 1	-	As per Table 2	As per Table 2	-	-	-	-
2	Functional Test 2	-	As per Table 2	As per Table 2	-	-	-	-
3	Functional Test 3	-	As per Table 2	As per Table 2	-	-	-	-
4 to 7	Quiescent Current 1	I_{DD1}	As per Table 2	As per Table 2	± 0.3	-	1.0	μA
8 to 17	Input Current Low Level	I_{IL}	As per Table 2	As per Table 2	± 20	-	-100	nA
18 to 27	Input Current High Level	I_{IH}	As per Table 2	As per Table 2	± 20	-	100	nA
52 to 59	Output Voltage Low Level 4	V_{OL4}	As per Table 2	As per Table 2	± 0.04	-	0.4	V
68 to 75	Output Voltage Low Level 6	V_{OL6}	As per Table 2	As per Table 2	± 0.04	-	0.4	V
108 to 115	Output Voltage High Level 4	V_{OH4}	As per Table 2	As per Table 2	± 0.2	2.4	-	V
124 to 131	Output Voltage High Level 6	V_{OH6}	As per Table 2	As per Table 2	± 0.2	4.7	-	V
160 to 167	Output Leakage Current Third State (Low Level Applied)	I_{OZL}	As per Table 2	As per Table 2	± 0.2	$-$	-0.5	μA
168 to 175	Output Leakage Current Third State (High Level Applied)	I_{OZH}	As per Table 2	As per Table 2	± 0.2	$-$	0.5	μA

NOTES

1. The change limits (Δ) are applicable to the Operating Life test only. The change in parameters between initial and end point measurements shall not exceed the limits given. In addition, the absolute limits shall not be exceeded.

FIGURE 6 - BIAS CONDITIONS FOR IRRADIATION TESTING

NOTES
1. Input Protection Resistor = 1.0kΩ.

TABLE 7 - ELECTRICAL MEASUREMENTS DURING AND ON COMPLETION OF IRRADIATION TESTING

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITIONS	CHANGE LIMITS (Δ)	ABSOLUTE		UNIT
						MIN	MAX	
1	Functional Test 1	-	As per Table 2	As per Table 2	-	-	-	-
2	Functional Test 2	-	As per Table 2	As per Table 2	-	-	-	-
3	Functional Test 3	-	As per Table 2	As per Table 2	-	-	-	-
4 to 7	Quiescent Current	I_{DD}	As per Table 2	As per Table 2	-	-	100	µA

APPENDIX 'A'   Page 1 of 1

AGREED DEVIATIONS FOR MOTOROLA (F)

ITEMS AFFECTED	DESCRIPTION OF DEVIATIONS
Para. 4.2.1(a)	Para. 5.2.2, Total Dose Irradiation Testing: Shall not be performed during qualification and maintenance of qualification.